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(12) **United States Design Patent**
Lee et al.

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(54) **PROBE PIN**

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(**) Term: **15 Years**

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(30) **Foreign Application Priority Data**

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(52) **U.S. Cl.**
USPC **D10/78**

(58) **Field of Classification Search**
USPC D4/101, 109; D19/115, 102; D13/182, D13/129, 199, 184; D24/215, 108, 224, D24/169; D10/81; D8/31, 107, 80; D26/46, 37
CPC G01R 1/0675; G01R 1/07357
See application file for complete search history.

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(57) **CLAIM**

The ornamental design for a probe pin, as shown and described.

DESCRIPTION

FIG. **1** is a front-right side-top perspective view depicting a probe pin according to the present invention.
FIG. **2** is a front view of the probe pin of FIG. **1**.
FIG. **3** is a rear view of the probe pin of FIG. **1**.
FIG. **4** is an enlarged left side view of the probe pin of FIG. **1**.
FIG. **5** is an enlarged right side view of the probe pin of FIG. **1**.
FIG. **6** is a top view of the probe pin of FIG. **1**; and,
FIG. **7** is a bottom view of the probe pin of FIG. **1**.
The broken lines depict portions of the article that form no part of the claimed design.
The probe pin according to the present invention is made of metal materials. The probe pin according to the present invention is used in testing electrical properties of a substrate or semiconductor used in information technology (IT) fields.

1 Claim, 7 Drawing Sheets

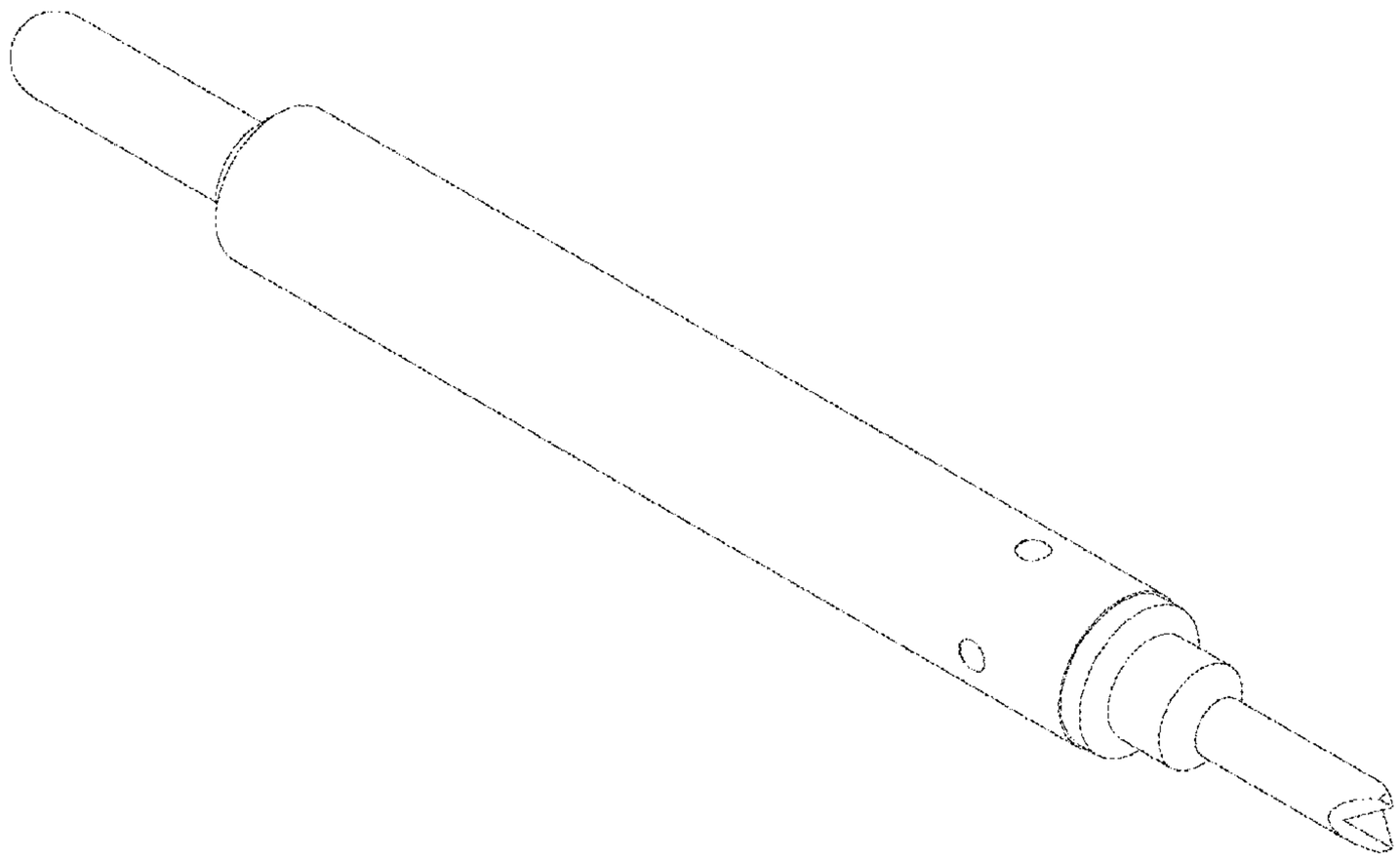

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FIG. 1

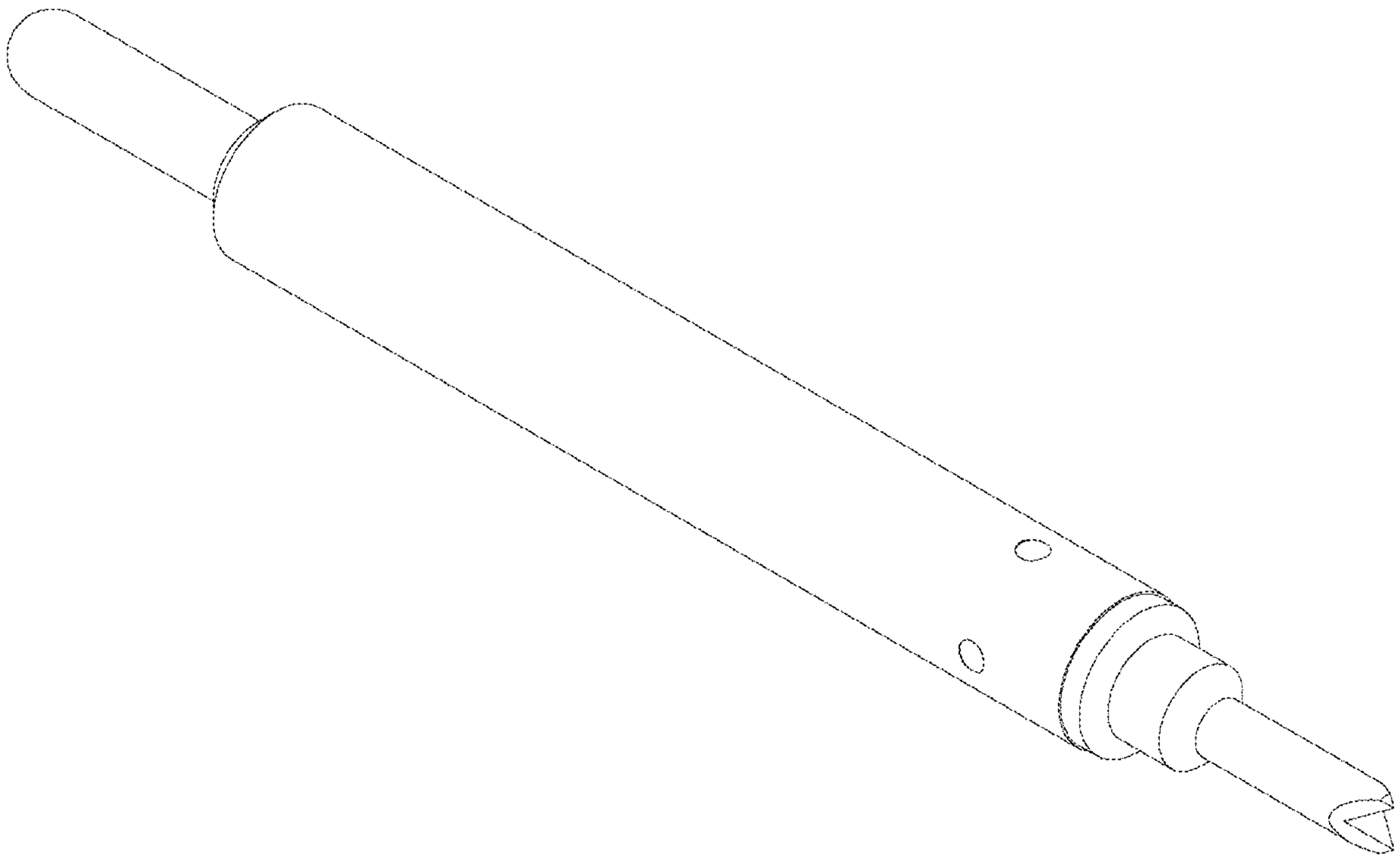


FIG. 2

FIG. 3

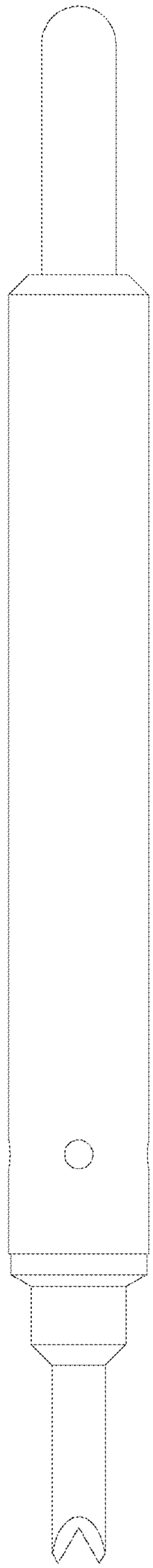


FIG. 4

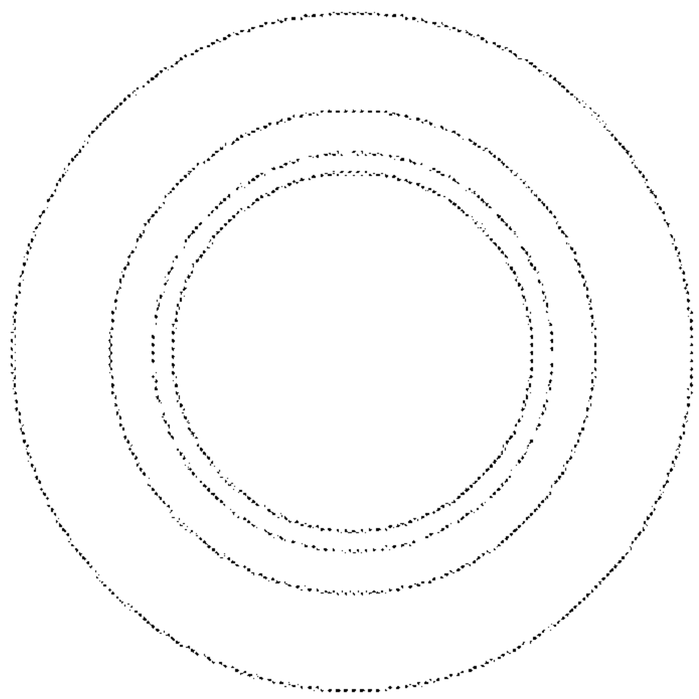
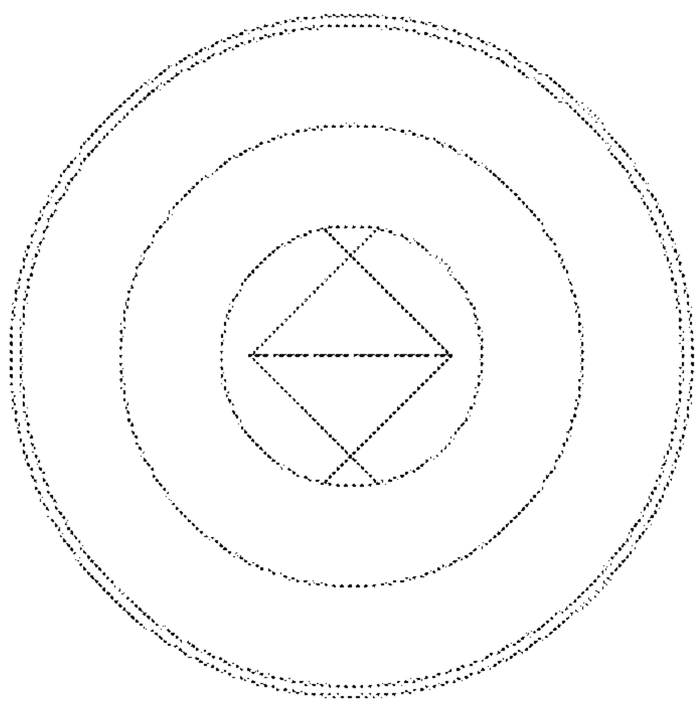


FIG. 5



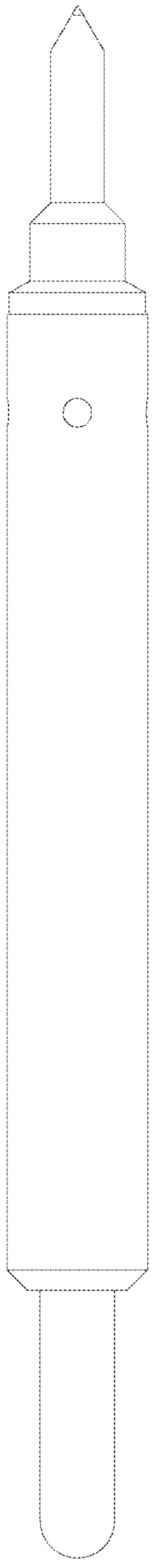


FIG. 6

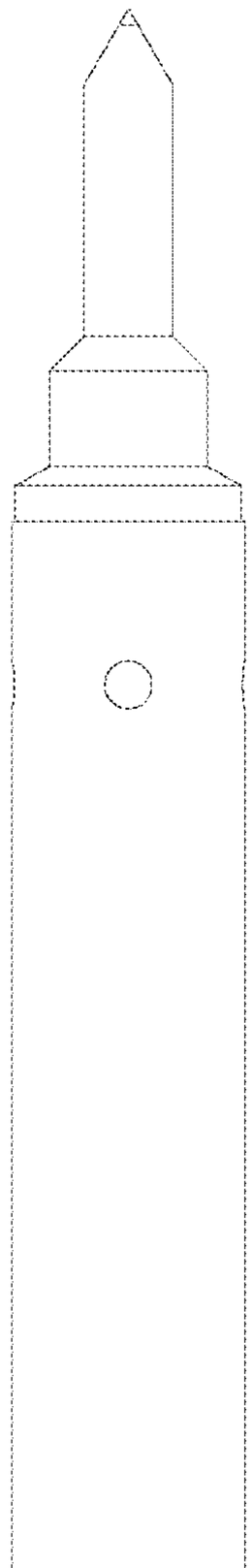


FIG. 7